

CYPRESS SEMICONDUCTOR CORPORATION PRODUCT RELIABILITY REPORT

QUARTER 1, 2000



PERFORM PER THE REQUIREMENT OF 25-00008, RELIABILITY MONITOR PROGRAM SPECIFICATION

Ed Russell
Reliability Director

STANDARD STRESS TEST DESCRIPTIONS

<u>TEST</u>	<u>DESCRIPTION</u>
EFRA/LFRA	High Temp Op Life, 150°C, Dynamic 115% V _{cc} Nominal
EFRA/LFRB	High Temp Op Life, 125°C, Dynamic 115% V _{cc} Nominal
HTSSLA	High Temp Steady State Life, 150°C, Static 115% V _{cc} Nominal
HTSSLB	High Temp Steady State Life, 125°C, Static 115% V _{cc} Nominal
DRET	Data Retention Test, Data Bake 165°C, Plastic
DRET2	Data Retention Test, Data Bake 250°C, Hermetic
PCT	Pressure Cooker Test, 121°C, 100%RH, No Bias
HAST	Hi-Accel Saturation Test, 140°C/130°C, 85%RH, Static 100% V _{cc}
TC1	Temp Cycle, 125°C to -40°C (Hermetic devices)
TC2	Temp Cycle, 125°C to -40°C
TC3	Temp Cycle, 150°C to -65°C
HTS	High Temp Storage, 150°C /165°C, No Bias

WAFER FAB AREAS

<u>FAB #</u>	<u>LOCATION</u>
CA	San Jose, California
TX	Round Rock, Texas
MN	Bloomington, Minnesota
TW	TSMC, Taiwan

ASSEMBLY LOCATION

<u>ID</u>	<u>COMPANY/LOCATION</u>
KOREA-A	Anam-Buchon/Korea
ASAT-B	Asat/Hongkong
USA-C	Cypress/USA
PHIL-D	Dynesem/Philippines
USA-E	Cypress-Minnesota/USA
INDNS-F	Astra/Indonesia
TAIWAN-G	ASE/Taiwan
KOREA-H	Hyundai/Korea
MALAY-J	ASE/Malaysia
THLAND-AK	TMS/Thailand
KOREA-L	Anam-Seoul/Korea
PHIL-M	Anam/Philippines
USA-N	Express/USA
INDNS-O	Omedata/Indonesia
USA-P	Pantronix/USA
KOREA-Q	Anam-Bupyong/Korea
CSPI-R	Cypress/Philippines
USA-S	ATM/USA
TAIWAN-T	OSE/Taiwan
MALAY-U	Unisem/Malaysia
USA-V	VLSA/USA
USA-W	Toshiba/USA
ALPHA-X	Alphatec/Thailand
THLAND-Z	Hana/Thailand
USA-AP	APLUS/USA
KOREA-GQ	Anam-Khangju/Korea
PHIL-GW	Gateway Electronics/Philippines

DESCRIPTION OF DATA TABLE COLUMN HEADINGS

<u>COLUMN HEADING</u>	<u>DESCRIPTION OF COLUMN CONTENTS</u>
Division	Cypress Manufacturing Division
Test	Common code for the stress performed. See table on previous page for detail.
Test Condition	Tem/humidity/bias condition for the stress. See table on previous for detail
Device ID	Cypress part number
Date Code	Week in which specific lot was marked/sealed/molded.
Lot Number	Manufacturing (assembly) lot number
Function	Generic product family at Cypress
Technology	Fabrication process technology.
Pkg Type	Common code for standard package configuration (PDIP=Plastic Dual-In-Line-Package).
Pkg Location	Country Location + Initial of assembly house (see table on previous page for detail).
# Pins	Pin cont of package in which device is assembled.
Duration	Data Readpoint of stress. For Temp Cycle (TC) = Cycles; all other stresses=Hours.
# Test	Quantity of devices submitted to this stress/test.
# Failed	Quantity of devices failing at this specific readpoint.
Fail Mode	Failure analysis results from this test, if any.

RELIABILITY DATA SUMMARY
(Q100)

LONG TERM FAILURE RATE SUMMARY					
PROCESS	DEVICE HOURS			FAILED	FAILURE MODE
	150C	125C	TOTAL* @ 150C		
E2PROM TOTAL	78,960	0	78,960	0	
CMOS-TSMC TOTAL	115,500	0	115,500	0	
FAMOS TOTAL	0	0	0	0	
FLASH TOTAL	0	0	0	0	
SRAM/LOGIC TOTAL	1,379,068	0	1,379,068	5	3 UNKNOWN/2 LOST DEVICE
BICMOS TOTAL	0	0	0	0	
LFR TOTAL	1,573,528	0	1,573,528	5	3 UNKNOWN/2 LOST DEVICE
EARLY FAILURE RATE SUMMARY					
PROCESS	UNITS TESTED			FAILED	FAILURE MODE
	150C	125C	TOTAL		
E2PROM TOTAL	671	0	671	0	
FAMOS TOTAL	0	0	0	0	
FLASH TOTAL	0	0	0	0	
SRAM/LOGIC TOTAL	46,203	0	46,203	6	2 PARTICLES/2DESTROY DURING ANALYSIS/2 POLY DEFECTS
BICMOS TOTAL	0	0	0	0	
EFR TOTAL	46,874	0	46,874	6	2 PARTICLES/2DESTROY DURING ANALYSIS/2 POLY DEFECTS
HTSSL FAILURE RATE SUMMARY					
PROCESS	DEVICE HOURS			FAILED	FAILURE MODE
	150C	125C	TOTAL* @ 150C		
FAMOS TOTAL	0	0	0	0	
FLASH TOTAL	0	0	0	0	
SRAM/LOGIC TOTAL	12,936	0	12,936	0	
BICMOS TOTAL	0	0	0	0	
HTSSL TOTAL	12,936	0	12,936	0	

* Equivalent Total Device Hours/Cycles. Derating factors are used for lower stress condition.

**RELIABILITY DATA SUMMARY
 (Q100)**

TEMP CYCLE FAILURE RATE SUMMARY					
PROCESS	UNITS TESTED			FAILED	FAILURE MODE
	1000Cys Condition C	2000Cys Condition B	TOTAL		
E2PROM TOTAL	587	392	979	0	
CMOS-TSMC TOTAL	432	0	432	0	
FAMOS TOTAL	90	0	90	0	
FLASH TOTAL	975	0	975	0	
SRAM/LOGIC TOTAL	3,875	565	4,440	14	2 OPEN BOND LIFT /8 TOPSIDE CRACK/2 OPEN HEEL/1 UNKNOWN/1 DESTROY DURING ANALYSIS
BICMOS TOTAL	87	0	87	0	
TC TOTAL	6,046	957	7,003	14	2 OPEN BOND LIFT/8 TOPSIDE CRACK/2 OPEN HEEL/1 UNKNOWN/1 DESTROY DURING ANALYSIS

HAST FAILURE RATE SUMMARY					
PROCESS	UNITS TESTED			FAILED	FAILURE MODE
	140C	130C	TOTAL		
E2PROM TOTAL	48	48	96	0	
CMOS-TSMC TOTAL	0	96	96	0	
FAMOS TOTAL	0	220	220	0	
FLASH TOTAL	0	376	376	0	
SRAM/LOGIC TOTAL	48	1,606	1,605	2	1 OPEN METAL/1 UNKNOWN
BICMOS TOTAL	0	45	45	0	
HAST TOTAL	96	2,391	2,487	2	1 OPEN METAL/1 UNKNOWN

RELIABILITY DATA SUMMARY
(Q100)

PCT FAILURE RATE SUMMARY			
PROCESS	UNITS TESTED	FAILED	FAILURE MODE
E2PROM TOTAL	326	2	2 SOLDERABILITY
FAMOS TOTAL	313	0	
FLASH TOTAL	629	0	
SRAM/LOGIC TOTAL	2,128	3	2 UNKNOWN/1 DELAMINATION IN TOPSIDE
BICMOS TOTAL	45	0	
PCT TOTAL	3,115	5	2 SOLDERABILITY/2 UNKNOWN/1 DELAMINATION IN TOPSIDE

Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
Wfr Process ID: CMOS-TSMC															
HAST	130C/5.5V	CPD	CLK	W49C65	99334		82703-700	TW	SSOP	CSPI-R	48	128	48	0	
	130C/5.5V	CPD	CLK	W49C65	99334		82703-800	TW	SSOP	CSPI-R	48	128	48	0	
HTS	150C/N/A	CPD	CLK	W49C65	99334		82703-700	TW	SSOP	CSPI-R	48	500	48	0	
	150C/N/A	CPD	CLK	W49C65	99334		82703-700	TW	SSOP	CSPI-R	48	1000	48	0	
LFRA	150C/5.75V	CPD	CLK	W49C65	99334		82703-700	TW	SSOP	CSPI-R	48	80	77	0	
	150C/5.75V	CPD	CLK	W49C65	99334		82703-700	TW	SSOP	CSPI-R	48	500	77	0	
	150C/5.75V	CPD	CLK	W49C65	99334		82703-800	TW	SSOP	CSPI-R	48	80	77	0	
	150C/5.75V	CPD	CLK	W49C65	99334		82703-800	TW	SSOP	CSPI-R	48	500	77	0	
	150C/5.75V	CPD	CLK	W49C65	99334		82703-900	TW	SSOP	CSPI-R	48	80	77	0	
	150C/5.75V	CPD	CLK	W49C65	99334		82703-900	TW	SSOP	CSPI-R	48	500	77	0	
T/C3	150C/-65C	CPD	CLK	W49C65	99334		82703-700	TW	SSOP	CSPI-R	48	300	48	0	
	150C/-65C	CPD	CLK	W49C65	99334		82703-700	TW	SSOP	CSPI-R	48	500	48	0	
	150C/-65C	CPD	CLK	W49C65	99334		82703-700	TW	SSOP	CSPI-R	48	1000	48	0	
	150C/-65C	CPD	CLK	W49C65	99334		82703-800	TW	SSOP	CSPI-R	48	300	48	0	
	150C/-65C	CPD	CLK	W49C65	99334		82703-800	TW	SSOP	CSPI-R	48	500	48	0	
	150C/-65C	CPD	CLK	W49C65	99334		82703-800	TW	SSOP	CSPI-R	48	1000	48	0	
	150C/-65C	CPD	CLK	W49C65	99334		82703-900	TW	SSOP	CSPI-R	48	300	48	0	
	150C/-65C	CPD	CLK	W49C65	99334		82703-900	TW	SSOP	CSPI-R	48	500	48	0	
	150C/-65C	CPD	CLK	W49C65	99334		82703-900	TW	SSOP	CSPI-R	48	1000	48	0	

Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
Wfr Process ID: BICMOS-SM1															
HAST	130C/3.63	DCD	CHNL	CY7B991-JC	MR001130	0001	619938492	TX	PLCC	ALPHA-X	32	128	45	0	
HTS	150C/N/A	DCD	CHNL	CY7B991-JC	MR94043	9938	619926775	TX	PLCC	ALPHA-X	32	500	45	0	
PCT	121C/100%RH	DCD	CHNL	CY7B991-JC	MR001128	0001	619938492	TX	PLCC	ALPHA-X	32	168	45	0	
T/C3	150C/-65C	DCD	CHNL	CY7B991-JC	MR001129	0001	619938492	TX	PLCC	ALPHA-X	32	300	45	0	
	150C/-65C	DCD	CHNL	CY7B9910-SC	MR94035	9940	519915425	TX	SOIC	INDNS-O	24	300	42	0	

Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
Wfr Process ID: E2PROM-E3															
EFRA	150C/5.75V	PLD	37K	CY37128P84-YMB	99455	9949	619936306	TW	CLCC	ALPHA-X	84	48	671	0	5 EOS
HAST	130C/3.63V	PLD	37K	CY37256VP256-BBC	99473	0001	619937560	TW	FBGA	TAIWN-G	256	128	48	0	
	140C/5.5V	PLD	37K	CY37512P208-NC	99234	9903	619817611	TW	PQFP	TAIWN-G	208	128	48	0	
HTS	165C/N/A	PLD	37K	CY37256VP256-BBC	99473	9926	619915336	TW	FBGA	TAIWN-G	256	336	48	0	
LFRA	150C/5.75C	PLD	37K	CY37064P44-YMB	99456	0002	610000497	TW	CLCC	ALPHA-X	44	80	524	0	5 EOS
	150C/5.75V	PLD	37K	CY37256P160-UMB	99457	9948	619935553	TW	CQFP	USA-GA	160	80	374	0	4 EOS
	150C/5.75V	PLD	37K	CY37512P208-UM	99461	9950	619935690	TW	CQFP	USA-GA	208	80	89	0	3 Bent Leads
PCT	121C/100%RH	PLD	37K	CY37032P44-JC	MR001147	9950	619935277	TW	PLCC	KOREA-A	44	168	45	0	
	121C/100%RH	PLD	37K	CY37032VP44-AC	MR001247	0005	610001062	TW	TQFP	TAIWN-G	44	168	45	0	
	121C/100%RH	PLD	37K	CY37064VP100-AC	MR001241	0005	610001831	TW	TQFP	TAIWN-G	100	168	45	0	
	121C/100%RH	PLD	37K	CY37128P84-JC	99455	9947	619935274	TW	PLCC	KOREA-A	84	168	48	0	
	121C/100%RH	PLD	37K	CY37128P84-JC	MR94281	9948	619932550	TW	PLCC	KOREA-A	84	168	50	0	
	121C/100%RH	PLD	37K	CY37256VP256-BBC	99473	9926	619915336	TW	FBGA	TAIWN-G	256	168	48	2	2 Solderability
	121C/100%RH	PLD	37K	CY37512P258-BGC	99461	9949	619935818	TW	BGA	TAIWN-G	292	168	45	0	
T/C1	150C/-65C	PLD	37K	CY37064P44-YMB	000606	0001	610000497	TW	CLCC	ALPHA-X	44	100	52	0	
	150C/-65C	PLD	37K	CY37064P44-YMB	000606	0001	610000497	TW	CLCC	ALPHA-X	44	1000	50	0	
T/C2	125C/-55C	PLD	37K	CY37128VP100-BBC	99473	0002	619938111	TW	FBGA	TAIWN-G	100	500	48	0	
	125C/-55C	PLD	37K	CY37128VP100-BBC	99473	0002	619938111	TW	FBGA	TAIWN-G	100	1500	48	0	
	125C/-55C	PLD	37K	CY37256VP256-BBC	99473	0001	619937560	TW	FBGA	TAIWN-G	256	500	50	0	
	125C/-55C	PLD	37K	CY37256VP256-BBC	99473	0001	619937560	TW	FBGA	TAIWN-G	256	1500	50	0	
	125C/-55C	PLD	37K	CY37256VP256-BBC	99473	0001	619937561	TW	FBGA	TAIWN-G	256	500	50	0	
	125C/-55C	PLD	37K	CY37256VP256-BBC	99473	0001	619937561	TW	FBGA	TAIWN-G	256	1500	50	0	

Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINS	DURATION	SAMP	REJ	FAILURE MODE
Wfr Process ID: E2PROM-E3															
T/C2	125C/-55C	PLD	37K	CY37256VP256-BBC	99473	9949	619937559	TW	FBGA	TAIWN-G	256	500	48	0	
	125C/-55C	PLD	37K	CY37256VP256-BBC	99473	9949	619937559	TW	FBGA	TAIWN-G	256	1500	48	0	
T/C3	150C/-65C	PLD	37K	CY37128P84-JC	99455	9947	619935274	TW	PLCC	KOREA-A	84	300	48	0	
	150C/-65C	PLD	37K	CY37128P84-JC	99455	9947	619935274	TW	PLCC	KOREA-A	84	500	48	0	
	150C/-65C	PLD	37K	CY37128P84-JC	99455	9947	619935274	TW	PLCC	KOREA-A	84	1000	48	0	
	150C/-65C	PLD	37K	CY37128P84-JC	MR94280	9948	619932550	TW	PLCC	KOREA-A	84	300	50	0	
	150C/-65C	PLD	37K	CY37256P208-NC	MR94082	9932	619921607	TW	PQFP	TAIWN-G	208	300	45	0	
	150C/-65C	PLD	37K	CY37256VP160-AC	99502	0002	619939025	TW	TQFP	TAIWN-G	160	300	50	0	
	150C/-65C	PLD	37K	CY37256VP160-AC	99502	0002	619939026	TW	TQFP	TAIWN-G	160	300	50	0	
	150C/-65C	PLD	37K	CY37256VP160-AC	99502	0002	619939027	TW	TQFP	TAIWN-G	160	300	50	0	
	150C/-65C	PLD	37K	CY37512P258-BGC	99461	9949	619935818	TW	BGA	TAIWN-G	292	300	48	0	
	150C/-65C	PLD	37K	CY37512P258-BGC	99461	9949	619935818	TW	BGA	TAIWN-G	292	500	48	0	

Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
Wfr Process ID: FAMOS-P20															
HAST	130C/5.5V	PLD	PLD	PALC22V10-JC	MR001117	9950	619937875	TX	PLCC	ALPHA-X	28	128	44	0	
	130C/5.5V	PLD	PLD	PALC22V10B-15PC	MR94236	9942	519916341	TX	PDIP	INDNS-O	24	128	45	0	
PCT	121C/100%RH	PLD	MAX	CY7C344-PC	MR001002	9952	619938203	TX	PDIP	ALPHA-X	28	168	45	0	
	121C/100%RH	PLD	PLD	PALC22V10-JC	MR001115	9950	619937875	TX	PLCC	ALPHA-X	28	168	45	0	

Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINS	DURATION	SAMP	REJ	FAILURE MODE
Wfr Process ID: FAMOS-P26															
HAST	130C/5.5V	IPD	USB	CY7C63000A-SC	MR94114	9944	619928386	TX	SOIC	CSPI-R	20	128	45	0	
	130C/5.5V	IPD	USB	CY7C63001A-SC	MR001204	0001	610000412	TX	SOIC	CSPI-R	20	128	41	0	
	130C/5.5V	IPD	USB	CY7C634121C-OC	MR001124	9950	619938008	TX	SSOP	CSPI-R	48	128	45	0	
HTS	150C/N/A	IPD	USB	CY7C63000A-SC	MR94115	9944	619928386	TX	SOIC	CSPI-R	20	500	45	0	
	150C/N/A	IPD	USB	CY7C63001A-SC	MR001205	0001	610000412	TX	SOIC	CSPI-R	20	500	45	0	
	150C/N/A	IPD	USB	CY7C63001A-SC	MR93018	9926	619918207	TX	SOIC	CSPI-R	20	500	45	0	
	150C/N/A	IPD	USB	CY7C63001A-SC	MR93018	9926	619918207	TX	SOIC	CSPI-R	20	1000	42	0	
	150C/N/A	IPD	USB	CY7C634121C-OC	MR001125	9950	619938008	TX	SSOP	CSPI-R	48	500	45	0	
	150C/N/A	IPD	USB	CY7C63413-OC	MR94104	9941	619927219	TX	SSOP	CSPI-R	48	500	45	0	
	150C/N/A	IPD	USB	CY7C63413-SC	MR001070	9952	619937138	TX	SOIC	ALPHA-X	24	500	45	0	
	150C/N/A	IPD	USB	CY7C634131C-SC	MR001052	9952	619940066	TX	SOIC	CSPI-R	24	500	45	0	
	150C/N/A	IPD	USB	CY7C65113-SC	MR94098	9935	619924810	TX	SOIC	ALPHA-X	28	500	45	0	
PCT	121C/100%RH	IPD	USB	CY7C63001A-SC	MR001202	0001	610000412	TX	SOIC	CSPI-R	20	168	45	0	
	121C/100%RH	IPD	USB	CY7C634121C-OC	MR001122	9950	619938008	TX	SSOP	CSPI-R	48	168	43	0	
	121C/100%RH	IPD	USB	CY7C63413-SC	MR001067	9952	619937138	TX	SOIC	ALPHA-X	24	168	45	0	
	121C/100%RH	IPD	USB	CY7C634131C-SC	MR001049	9952	619940066	TX	SOIC	CSPI-R	24	168	45	0	
	121C/100%RH	IPD	USB	CY7C65113-SC	MR94096	9935	619924810	TX	SOIC	ALPHA-X	28	168	45	0	
T/C3	150C/-65C	IPD	USB	CY7C63000A-SC	MR94113	9944	619928386	TX	SOIC	CSPI-R	20	300	45	0	
	150C/-65C	IPD	USB	CY7C63413-OC	MR94102	9941	619927219	TX	SSOP	CSPI-R	48	300	45	0	

Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
Wfr Process ID: FLASH-FL28D															
HAST	130C/5.5V	PLD	FLASH	CY7C371-JC	MR001028	9949	619937632	TX	PLCC	ALPHA-X	44	128	34	0	
	130C/5.5V	PLD	FLASH	CY7C371-JC	MR001033	9949	619937632	TX	PLCC	ALPHA-X	44	128	45	0	
	130C/5.5V	PLD	FLASH	CY7C373I-JC	000102	9936	619925111	TX	PLCC	PHIL-M	84	100	54	0	
	130C/5.5V	PLD	FLASH	CY7C373I-JC	MR001023	9936	619925111	TX	PLCC	PHIL-M	84	128	54	0	
	130C/5.5V	PLD	FLASH	CY7C373I-JC	MR94061	9927	619918706	TX	PLCC	PHIL-M	84	128	45	0	
	130C/5.5V	PLD	FLASH	CY7C374I-JC	000203	9952	619937601	TX	PLCC	ALPHA-X	84	94	50	0	
	130C/5.5V	PLD	FLASH	CY7C375I-AC	000303	9918	619909347	TX	TQFP	TAIWN-G	160	128	25	0	
	130C/5.5V	PLD	PLD	PALC22V10D-JC	MR001019	9952	519919372	TX	PLCC	INDNS-O	28	128	45	0	
HTS	165C/N/A	PLD	FLASH	CY7C375I-AC	000303	9918	619909347	TX	TQFP	TAIWN-G	160	336	50	0	
PCT	121C/100%RH	PLD	FLASH	CY7C371-JC	MR001026	9949	619937632	TX	PLCC	ALPHA-X	44	168	45	0	
	121C/100%RH	PLD	FLASH	CY7C371-JC	MR001031	9949	619937632	TX	PLCC	ALPHA-X	44	168	45	0	
	121C/100%RH	PLD	FLASH	CY7C373I-JC	000102	9927	619918706	TX	PLCC	PHIL-M	84	168	50	0	
	121C/100%RH	PLD	FLASH	CY7C373I-JC	000102	9935	619923963	TX	PLCC	PHIL-M	84	168	52	0	
	121C/100%RH	PLD	FLASH	CY7C373I-JC	000102	9945	619931928	TX	PLCC	PHIL-M	84	168	50	0	
	121C/100%RH	PLD	FLASH	CY7C373I-JC	000203	9952	619937599	TX	PLCC	ALPHA-X	84	168	50	0	
	121C/100%RH	PLD	FLASH	CY7C373I-JC	MR001007	9949	619936176	TX	PLCC	PHIL-M	84	168	45	0	
	121C/100%RH	PLD	FLASH	CY7C373I-JC	MR001012	9949	619936176	TX	PLCC	PHIL-M	84	168	45	0	
	121C/100%RH	PLD	FLASH	CY7C373I-JC	MR001021	9935	619923963	TX	PLCC	PHIL-M	84	168	52	0	
	121C/100%RH	PLD	FLASH	CY7C373I-JC	MR94278	9946	619931928	TX	PLCC	PHIL-M	84	168	50	0	
	121C/100%RH	PLD	FLASH	CY7C373I-JC	MR94284	9929	619918706	TX	PLCC	PHIL-M	84	168	50	0	
	121C/100%RH	PLD	FLASH	CY7C374I-JC	000203	9952	619937601	TX	PLCC	ALPHA-X	84	168	50	0	

Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
Wfr Process ID: FLASH-FL28D															
PCT	121C/100%RH	PLD	PLD	PALC22V10D-JC	MR001017	9952	519919372	TX	PLCC	INDNS-O	28	168	45	0	
T/C3	150C/-65C	PLD	FLASH	CY7C371-JC	MR001027	9949	619937632	TX	PLCC	ALPHA-X	44	300	45	0	
	150C/-65C	PLD	FLASH	CY7C371-JC	MR001032	9949	619937632	TX	PLCC	ALPHA-X	44	300	45	0	
	150C/-65C	PLD	FLASH	CY7C373I-JC	000102	9927	619918706	TX	PLCC	PHIL-M	84	300	50	0	
	150C/-65C	PLD	FLASH	CY7C373I-JC	000102	9945	619931928	TX	PLCC	PHIL-M	84	300	50	0	
	150C/-65C	PLD	FLASH	CY7C373I-JC	000203	9952	619937599	TX	PLCC	ALPHA-X	84	300	50	0	
	150C/-65C	PLD	FLASH	CY7C373I-JC	000203	9952	619937600	TX	PLCC	ALPHA-X	84	300	50	0	
	150C/-65C	PLD	FLASH	CY7C373I-JC	MR001013	9949	619936176	TX	PLCC	PHIL-M	84	300	45	0	
	150C/-65C	PLD	FLASH	CY7C373I-JC	MR94277	9946	619931928	TX	PLCC	PHIL-M	84	300	50	0	
	150C/-65C	PLD	FLASH	CY7C373I-JC	MR94283	9929	619918706	TX	PLCC	PHIL-M	84	300	50	0	
	150C/-65C	PLD	FLASH	CY7C374I-JC	000203	9952	619937601	TX	PLCC	ALPHA-X	84	300	50	0	
	150C/-65C	PLD	FLASH	CY7C375I-AC	000303	9918	619909347	TX	TQFP	TAIWN-G	160	300	50	0	
	150C/-65C	PLD	FLASH	CY7C375I-AC	000303	9918	619909347	TX	TQFP	TAIWN-G	160	500	48	0	
	150C/-65C	PLD	FLASH	CY7C375I-AC	000303	9918	619909347	TX	TQFP	TAIWN-G	160	1000	48	0	
	150C/-65C	PLD	FLASH	CY7C375I-AC	000303	9918	619909600	TX	TQFP	TAIWN-G	160	300	50	0	
	150C/-65C	PLD	FLASH	CY7C375I-AC	000303	9918	619909600	TX	TQFP	TAIWN-G	160	500	50	0	
	150C/-65C	PLD	FLASH	CY7C375I-AC	000303	9918	619909600	TX	TQFP	TAIWN-G	160	1000	49	0	
	150C/-65C	PLD	FLASH	CY7C375I-AC	000303	9918	619909601	TX	TQFP	TAIWN-G	160	300	50	0	
	150C/-65C	PLD	FLASH	CY7C375I-AC	000303	9918	619909601	TX	TQFP	TAIWN-G	160	500	50	0	
	150C/-65C	PLD	FLASH	CY7C375I-AC	000303	9918	619909601	TX	TQFP	TAIWN-G	160	1000	50	0	
	150C/-65C	PLD	FLASH	CY7C375I-AC	MR94247	9945	619929003	TX	TQFP	KOREA-Q	160	300	45	0	

Quarterly Reliability Monitor Data - 00Q1

<i>STRESS</i>	<i>TEST COND</i>	<i>DIV</i>	<i>FUNCTION</i>	<i>DEVICE</i>	<i>EVAL #</i>	<i>DC</i>	<i>ASSY LOT</i>	<i>FAB</i>	<i>PKG</i>	<i>PKG</i>	<i># PINS</i>	<i>DURATION</i>	<i>SAMP</i>	<i>REJ</i>	<i>FAILURE MODE</i>
Wfr Process ID: SRAM/LOGIC-L20															
T/C2	125C/-55C	DCD	VME	CY7C611A-NC	M99362	9924	619916051	TX	PQFP	ASAT-B	160	500	49	0	
	125C/-55C	DCD	VME	CY7C611A-NC	M99362	9924	619916051	TX	PQFP	ASAT-B	160	1000	46	2	2 Open- Bond Lift (Die)/1 EOS
	125C/-55C	DCD	VME	CY7C611A-NC	M99362	9924	619916051	TX	PQFP	ASAT-B	160	1500	44	8	8 Topside Crack

Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
Wfr Process ID: SRAM/LOGIC-L27															
HTS	165C/N/A	DCD	PCLOG	CY82C693-NC	99234	9915	619909669	MN	PQFP	TAIWN-G	208	336	48	0	
PCT	121C/100%RH/	DCD	PCLOG	CY82C693-NC	99234	9915	619909669	MN	PQFP	TAIWN-G	208	168	48	1	1 Delamination in Topside
T/C3	150C/-65C	DCD	PCLOG	CY82C693-NC	99234	9915	619909669	MN	PQFP	TAIWN-G	208	300	48	0	
	150C/-65C	DCD	PCLOG	CY82C693-NC	99234	9915	619909669	MN	PQFP	TAIWN-G	208	1000	48	0	
	150C/-65C	DCD	PCLOG	CY82C693-NC	99234	9915	619909669	MN	PQFP	TAIWN-G	208	300	48	0	
	150C/-65C	DCD	PCLOG	CY82C693-NC	99234	9915	619909669	MN	PQFP	TAIWN-G	208	1000	48	0	
	150C/-65C	DCD	PCLOG	CY82C693-NC	99234	9915	619909669	MN	PQFP	TAIWN-G	208	300	48	0	
	150C/-65C	DCD	PCLOG	CY82C693-NC	99234	9915	619909669	MN	PQFP	TAIWN-G	208	1000	48	0	

Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
Wfr Process ID: SRAM/LOGIC-L28															
EFRA	150C/3.8V	CPD	CLK	CY2280PVC-OC	99285	9938	619927291	TW	SSOP	CSPI-R	48	48	334	0	1 EOS
	150C/3.8V	CPD	CLK	CY2280PVC-OC	99285	9940	619928659	TW	SSOP	CSPI-R	48	48	234	0	
	150C/3.8V	CPD	CLK	CY2280PVC-OC	99285	9940	619928659	TW	SSOP	CSPI-R	48	48	101	0	
	150C/3.8V	CPD	CLK	CY2280PVC-OC	99285	9945	619933793	TW	SSOP	CSPI-R	48	48	343	0	7 EOS
	150C/5.75V	CPD	CLK	CY22037AES	000402	0004	610003291	TX	SOIC	CSPI-R	20	48	500	0	
	150C/5.75V	CPD	CLK	CY22037AES	000402	0004	610003291	TX	SOIC	CSPI-R	20	48	500	0	
	150C/5.75V	CPD	CLK	CY22037AES	001103	0004	610003291	TW	SOIC	CSPI-R	20	48	500	0	
	150C/5.75V	CPD	CLK	CY22037AES	001103	0004	610003291	TW	SOIC	CSPI-R	20	48	500	0	
HAST	130C/3.63V	CPD	CLK	CY2280PVC-OC	99285	9938	619927291	TW	SSOP	CSPI-R	48	128	50	0	
	130C/3.63V	CPD	CLK	CY2280PVC-OC	99285	9938	619927291	TW	SSOP	CSPI-R	48	128	50	0	
	130C/3.63V	CPD	CLK	CY2280PVC-OC	99285	9940	619928659	TW	SSOP	CSPI-R	48	128	50	0	
HTS	150C/3.63V	CPD	CLK	CY2280PVC-OC	99285	9938	619927291	TW	SSOP	CSPI-R	48	80	77	0	
	150C/3.63V	CPD	CLK	CY2280PVC-OC	99285	9938	619927291	TW	SSOP	CSPI-R	48	168	77	0	
	150C/N/A	CPD	CLK	CY2210PVC	MR001046	9945	619933123	TX	SSOP	CSPI-R	56	500	45	0	
	150C/N/A	CPD	CLK	CY2287PVC	MR94109	9936	619925423	TX	SSOP	CSPI-R	56	500	45	0	
LFRA	150C/3.8V	CPD	CLK	CY2280PVC-OC	99285	9938	619927291	TW	SSOP	CSPI-R	48	80	120	0	
	150C/3.8V	CPD	CLK	CY2280PVC-OC	99285	9938	619927291	TW	SSOP	CSPI-R	48	500	120	0	
	150C/3.8V	CPD	CLK	CY2280PVC-OC	99285	9940	619928659	TW	SSOP	CSPI-R	48	80	120	0	
	150C/3.8V	CPD	CLK	CY2280PVC-OC	99285	9940	619928659	TW	SSOP	CSPI-R	48	500	120	0	
	150C/3.8V	CPD	CLK	CY2280PVC-OC	99285	9945	619933793	TW	SSOP	CSPI-R	48	80	123	0	2 EOS
	150C/3.8V	CPD	CLK	CY2280PVC-OC	99285	9945	619933793	TW	SSOP	CSPI-R	48	500	123	0	
PCT	121C/100%RH	CPD	CLK	CY2210PVC	MR001043	9945	619933123	TX	SSOP	CSPI-R	56	168	44	0	

Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINS	DURATION	SAMP	REJ	FAILURE MODE
Wfr Process ID: SRAM/LOGIC-L28															
PCT	121C/100%RH	CPD	CLK	CY2254ASC	MR001037	9949	619937357	TX	SOIC	CSPI-R	28	168	43	0	
	121C/100%RH	CPD	CLK	CY2277APAC	MR001061	9952	619939685	TX	TSOP	CSPI-R	48	168	44	0	
	121C/100%RH	CPD	CLK	CY2280PVC-OC	99285	9938	619927291	TW	SSOP	CSPI-R	48	168	53	0	
	121C/100%RH	CPD	CLK	CY2280PVC-OC	99285	9938	619927291	TW	SSOP	CSPI-R	48	168	53	0	
	121C/100%RH	CPD	CLK	CY2280PVC-OC	99285	9940	619928659	TW	SSOP	CSPI-R	48	168	50	0	
	121C/100%RH	IPD	FCY	CY74FCT377*TQC	MR001190	0002	610000660	TX	SSOP	CSPI-R	20	168	38	0	
T/C3	150C/-65C	CPD	CLK	CY2280PVC-OC	99285	9938	619927291	TW	SSOP	CSPI-R	48	300	50	0	
	150C/-65C	CPD	CLK	CY2280PVC-OC	99285	9938	619927291	TW	SSOP	CSPI-R	48	300	50	0	
	150C/-65C	CPD	CLK	CY2280PVC-OC	99285	9940	619928659	TW	SSOP	CSPI-R	48	300	50	0	
	150C/-65C	CPD	CLK	CY2280PVC-OC	99285	9945	619933793	TW	SSOP	CSPI-R	48	300	45	0	

Quarterly Reliability Monitor Data - 00Q1

STRESS TEST COND DIV FUNCTION DEVICE EVAL # DC ASSY LOT FAB PKG PKG # PINS DURATION SAMP REJ FAILURE MODE

*****Wfr Process ID***: SRAM/LOGIC-L31**

PCT 121C/100%RH IPD FCT CY74FCT163543*PA MR001196 9952 619939264 MN TSOP CSPI-R 56 168 44 0

Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
Wfr Process ID: SRAM/LOGIC-R28															
HAST	130C/5.5V	DCD	DPORT	CY7C024-AC	MR001162	0002	619938224	TX	TQFP	TAIWN-G	100	128	45	0	
	130C/5.5V	DCD	FIFO	CY7C4245-JC	MR001136	0002	619938073	TX	PLCC	PHIL-M	68	128	45	0	
	130C/5.5V	DCD	FIFO	CY7C4801-AC	99423	9948	619932227	TX	TQFP	TAIWN-G	64	128	50	0	
	130C/5.5V	DCD	FIFO	CY7C4801-AC	99423	9948	619932227	TX	TQFP	TAIWN-G	64	256	50	0	
	130C/5.5V	MPD	SRAM	CY7C188-VC	MR94005	9932	619922430	TX	SOJ	CSPI-R	32	128	44	1	1 EOS /1 Open Metal (Due to Void)
	130C/5.5V	MPD	SRAM	CY7C192-VC	MR001210	0002	619938503	TX	SOJ	ALPHA-X	28	128	45	0	
HTS	150C/N/A	DCD	FIFO	CY7C420-PC	MR94259	9946	519915899	TX	PDIP	INDNS-O	28	500	45	0	
	150C/N/A	DCD	FIFO	CY7C421-VC	MR94264	9944	619930419	TX	SOJ	CSPI-R	28	500	45	0	
	150C/N/A	DCD	FIFO	CY7C4801-AC	99423	9948	619932227	TX	TQFP	TAIWN-G	64	500	50	0	
	150C/N/A	DCD	FIFO	CY7C4801-AC	99423	9948	619932227	TX	TQFP	TAIWN-G	64	1000	50	0	
	150C/N/A	MPD	SRAM	CY7C192-VC	MR001211	0002	619938503	TX	SOJ	ALPHA-X	28	500	45	0	
PCT	121C/100%RH	DCD	DPORT	CY7C024-AC	MR001160	0002	619938224	TX	TQFP	TAIWN-G	100	168	45	0	
	121C/100%RH	DCD	DPORT	CY7C136-NC	MR001140	9950	619937010	TX	PQFP	ASAT-B	52	168	45	0	
	121C/100%RH	DCD	FIFO	CY7C421-VC	MR94262	9944	619930419	TX	SOJ	CSPI-R	28	168	45	0	
	121C/100%RH	DCD	FIFO	CY7C4245-JC	MR001134	0002	619938073	TX	PLCC	PHIL-M	68	168	45	1	1 Unknown
	121C/100%RH	DCD	FIFO	CY7C4801-AC	99423	9948	619932227	TX	TQFP	TAIWN-G	64	168	50	0	
	121C/100%RH	MPD	SRAM	CY7C192-VC	MR001208	0002	619938503	TX	SOJ	ALPHA-X	28	168	45	0	
T/C3	150C/-65C	DCD	DPORT	CY7C024-AC	MR001161	0002	619938224	TX	TQFP	TAIWN-G	100	300	45	0	
	150C/-65C	DCD	DPORT	CY7C136-NC	99234	9946	619933453	CA	PQFP	ASAT-B	52	300	50	0	
	150C/-65C	DCD	DPORT	CY7C136-NC	99234	9947	619935705	CA	PQFP	TAIWN-G	52	300	50	0	
	150C/-65C	DCD	DPORT	CY7C136-NC	99234	9947	619935705	CA	PQFP	TAIWN-G	52	300	50	0	

Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINS	DURATION	SAMP	REJ	FAILURE MODE
Wfr Process ID: SRAM/LOGIC-R28															
T/C3	150C/-65C	DCD	DPORT	CY7C136-NC	99234	9947	619935705	CA	PQFP	TAIWN-G	52	300	50	0	
	150C/-65C	DCD	DPORT	CY7C136-NC	MR001141	9950	619937010	TX	PQFP	ASAT-B	52	300	45	0	
	150C/-65C	DCD	FIFO	CY7C420-PC	MR94258	9946	519915899	TX	PDIP	INDNS-O	28	300	45	0	
	150C/-65C	DCD	FIFO	CY7C421-VC	MR94263	9944	619930419	TX	SOJ	CSPI-R	28	300	45	0	
	150C/-65C	DCD	FIFO	CY7C4801-AC	99423	9948	619932226	TX	TQFP	TAIWN-G	64	300	49	0	
	150C/-65C	DCD	FIFO	CY7C4801-AC	99423	9948	619932227	TX	TQFP	TAIWN-G	64	300	50	0	
	150C/-65C	DCD	FIFO	CY7C4801-AC	99423	9948	619932228	TX	TQFP	TAIWN-G	64	300	50	0	
	150C/-65C	MPD	SRAM	CY7C188-VC	MR94004	9932	619922430	TX	SOJ	CSPI-R	32	300	45	0	
	150C/-65C	MPD	SRAM	CY7C192-VC	MR001209	0002	619938503	TX	SOJ	ALPHA-X	28	300	45	0	

Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
Wfr Process ID: SRAM/LOGIC-R32															
EFRA	150C/5.75V	MPD	SRAM	CY62256-SNC	MR92106	9915	519906723	CA	SOIC	INDNS-O	28	48	149	0	
HAST	130C/5.5V	MPD	SRAM	CY62128-ZI	MR94195	9940	619904071	MN	TSOP	TAIWN-G	32	128	39	0	
LFRA	150C/5.75V	MPD	SRAM	CY62256-SNC	MR92106	9915	519906723	CA	SOIC	INDNS-O	28	96	148	1	1 Unknown Cause
	150C/5.75V	MPD	SRAM	CY62256-SNC	MR92106	9915	519906723	CA	SOIC	INDNS-O	28	500	147	1	1 Unknown Cause
T/C3	150C/-65C	MPD	SRAM	CY62256-SNC	MR94230	9942	619930304	CA	NSOIC	CSPI-R	28	300	45	0	

Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINS	DURATION	SAMP	REJ	FAILURE MODE
Wfr Process ID: SRAM/LOGIC-R42															
HTS	150C/N/A	MPD	SRAM	CY62127V-BAI	000204		619938873	MN	FPBGA	CSPI-R	48	500	50	0	
	150C/N/A	MPD	SRAM	CY62127V-BAI	000204		619938873	MN	FPBGA	CSPI-R	48	1000	50	0	
PCT	121C/100%RH	MPD	SRAM	CY62127V-BAI	000204		619938675	MN	FPBGA	CSPI-R	48	168	43	0	
	121C/100%RH	MPD	SRAM	CY62127V-BAI	000204		619938873	MN	FPBGA	CSPI-R	48	168	46	0	
T/C3	150C/-65C	MPD	SRAM	CY62126V-ZSI	MR94140	9935	619922725	MN	TSOP II	CSPI-R	44	300	50	0	
	150C/-65C	MPD	SRAM	CY62127V-BAI	000204		619938675	MN	FPBGA	CSPI-R	48	300	45	0	
	150C/-65C	MPD	SRAM	CY62127V-BAI	000204		619938873	MN	FPBGA	CSPI-R	48	300	47	0	

Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ FAILURE MODE
Wfr Process ID: SRAM/LOGIC-R42D														
EFRA	150C/3.80	DCD	FIFO	CY7C4385-SI	MR93227	9933	619922486	MN	TQFP	KOREA-Q	64	48	143	0
	150C/3.8V	MPD	SRAM	CY7C1020V33-ZSC	000501	0002	610001575	MN	TSOP II	CSPI-R	44	48	6952	0
	150C/3.8V	MPD	SRAM	CY7C1049V33-VC	99358	9948	619934908	MN	SOJ	KOREA-L	36	48	3980	0
	150C/3.8V	MPD	SRAM	CY7C1049V33-VC	99358	9948	619934909	MN	SOJ	KOREA-L	36	48	3387	0
	150C/3.8V	MPD	SRAM	CY7C1333-AC	MR92099	9901	619817590	MN	TQFP	CSPI-R	100	48	146	0 2 EOS
HAST	130C/3.63	MPD	SRAM	CY7C1021V33-VC	MR001185	0001	619938884	MN	SOJ	TAIWN-G	44	128	45	0
	130C/3.63V	MPD	SRAM	CY7C1021V33-ZSC	MR001173	9950	619935798	MN	TSOP II	KOREA-H	44	128	45	0
	130C/3.63V	MPD	SRAM	CY7C1049V33-VC	MR001231	0003	619939542	MN	SOJ	CSPI-R	36	128	45	0
HTS	150C/N/A	MPD	SRAM	CY7C1021V33-VC	MR001186	0001	619938884	MN	SOJ	TAIWN-G	44	500	45	0
	150C/N/A	MPD	SRAM	CY7C1021V33-ZSC	MR001174	9950	619935798	MN	TSOP II	KOREA-H	44	500	45	0
	150C/N/A	MPD	SRAM	CY7C1049V33-VC	MR001232	0003	619939542	MN	SOJ	CSPI-R	36	500	45	0
	150C/N/A	MPD	SRAM	CY7C1049V33-VC	MR94243	9945	619929938	MN	SOJ	CSPI-R	36	500	45	0
	150C/N/A	MPD	SRAM	CY7C1334-AC	MR94202	9941	619927329	MN	TQFP	CSPI-R	100	500	45	0
LFRA	150C/3.80V	DCD	FIFO	CY7C4385-SI	MR93227	9933	619922486	MN	TQFP	KOREA-Q	64	500	143	0
	150C/3.8V	MPD	SRAM	CY7C1333-AC	MR92099	9901	619817590	MN	TQFP	CSPI-R	100	96	143	0 3 EOS
	150C/3.8V	MPD	SRAM	CY7C1333-AC	MR92099	9901	619817590	MN	TQFP	CSPI-R	100	500	142	0
PCT	121C/100%RH	MPD	SRAM	CY7C1021V33-VC	MR001183	0001	619938884	MN	SOJ	TAIWN-G	44	168	45	0
	121C/100%RH	MPD	SRAM	CY7C1021V33-ZSC	MR001171	9950	619935798	MN	TSOP II	KOREA-H	44	168	45	0
	121C/100%RH	MPD	SRAM	CY7C1049V33-VC	MR001229	0003	619939542	MN	SOJ	CSPI-R	36	168	45	0
	121C/100%RH	MPD	SRAM	CY7C1345-AC	MR001235	9952	619937704	MN	TQFP	CSPI-R	100	168	45	0
T/C3	150C/-65C	MPD	SRAM	CY7C1021V33-VC	MR001184	0001	619938884	MN	SOJ	TAIWN-G	44	300	45	0
	150C/-65C	MPD	SRAM	CY7C1021V33-ZSC	MR001172	9950	619935798	MN	TSOP II	KOREA-H	44	300	45	0

Quarterly Reliability Monitor Data - 00Q1

<i>STRESS</i>	<i>TEST COND</i>	<i>DIV</i>	<i>FUNCTION</i>	<i>DEVICE</i>	<i>EVAL #</i>	<i>DC</i>	<i>ASSY LOT</i>	<i>FAB</i>	<i>PKG</i>	<i>PKG</i>	<i># PINS</i>	<i>DURATION</i>	<i>SAMP</i>	<i>REJ</i>	<i>FAILURE MODE</i>
Wfr Process ID: SRAM/LOGIC-R42D															
T/C3	150C/-65C	MPD	SRAM	CY7C1049V33-VC	MR001230	0003	619939542	MN	SOJ	CSPI-R	36	300	45	0	
	150C/-65C	MPD	SRAM	CY7C1049V33-VC	MR94241	9945	619929938	MN	SOJ	CSPI-R	36	300	45	0	
	150C/-65C	MPD	SRAM	CY7C1334-AC	MR94200	9941	619927329	MN	TQFP	CSPI-R	100	300	44	0	
	150C/-65C	MPD	SRAM	CY7C1345-AC	MR94136	9941	619924444	MN	TQFP	CSPI-R	100	300	50	0	
	150C/-65C	MPD	SRAM	CY7C1345-AC	MR94137	9941	619924444	MN	TQFP	CSPI-R	100	300	47	0	
	150C/-65C	MPD	SRAM	CY7C1352-AC	MR94134	9939	619913649	MN	TQFP	CSPI-R	100	300	46	0	

Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
Wfr Process ID: SRAM/LOGIC-R42H															
EFRA	150C/5.75	MPD	SRAM	CY62128-ZAC	MR91134	9829	619807930	MN	STSOP	CSPI-R	32	48	148	0	1 EOS
HAST	130C/5.5V	MPD	SRAM	C62128A-ZAI	MR94273	9938	619926232	MN	STSOP	CSPI-R	32	128	45	0	
	130C/5.5V	MPD	SRAM	CY62128-SC	MR001098	9952	619937646	MN	SOIC	CSPI-R	32	128	45	0	
	130C/5.5V	MPD	SRAM	CY62256-SNC	MR001167	9949	619935207	MN	NSOIC	CSPI-R	28	128	38	0	
	130C/5.5V	MPD	SRAM	CY62256-SNI	MR94182	9942	519915797	MN	SOIC	INDNS-O	28	128	30	0	
HTS	150C/N/A	MPD	SRAM	C62128A-ZAI	MR94274	9938	619926232	MN	STSOP	CSPI-R	32	500	45	0	
	150C/N/A	MPD	SRAM	CY62128-SC	MR001099	9952	619937646	MN	SOIC	CSPI-R	32	500	44	0	
	150C/N/A	MPD	SRAM	CY62128-ZAC	MR001076	0001	619938583	MN	STSOP	CSPI-R	32	500	45	0	
	150C/N/A	MPD	SRAM	CY62256-SNC	MR001168	9949	619935207	MN	NSOIC	CSPI-R	28	500	45	0	
	150C/N/A	MPD	SRAM	CY62256-SNC	MR001219	0005	510000798	MN	NSOIC	INDNS-O	28	500	45	0	
	150C/N/A	MPD	SRAM	CY62256-ZC	MR001111	9952	619938545	MN	TSOP	CSPI-R	28	500	45	0	
LFRA	150C/5.75	MPD	SRAM	CY62128-ZAC	MR91134	9829	619807930	MN	STSOP	CSPI-R	32	96	146	0	
	150C/5.75	MPD	SRAM	CY62128-ZAC	MR91134	9829	619807930	MN	STSOP	CSPI-R	32	500	142	0	
PCT	121C/100%RH	MPD	SRAM	C62128A-ZAI	MR94271	9938	619926232	MN	STSOP	CSPI-R	32	168	45	0	
	121C/100%RH	MPD	SRAM	CY62128-SC	MR001096	9952	619937646	MN	SOIC	CSPI-R	32	168	44	0	
	121C/100%RH	MPD	SRAM	CY62128-ZAC	MR001073	0001	619938583	MN	STSOP	CSPI-R	32	168	45	0	
	121C/100%RH	MPD	SRAM	CY62256-SNC	MR001165	9949	619935207	MN	NSOIC	CSPI-R	28	168	38	0	
	121C/100%RH	MPD	SRAM	CY62256-SNC	MR001216	0005	510000798	MN	NSOIC	INDNS-O	28	168	45	0	
	121C/100%RH	MPD	SRAM	CY62256-ZC	MR001108	9952	619938545	MN	TSOP	CSPI-R	28	168	45	0	
T/C3	150C/-65C	MPD	SRAM	C62128A-ZAI	MR94272	9938	619926232	MN	STSOP	CSPI-R	32	300	45	0	
	150C/-65C	MPD	SRAM	CY62128-SC	MR001097	9952	619937646	MN	SOIC	CSPI-R	32	300	45	1	1 Unknown
	150C/-65C	MPD	SRAM	CY62128-ZAC	MR001074	0001	619938583	MN	STSOP	CSPI-R	32	300	45	0	

Quarterly Reliability Monitor Data - 00Q1

<i>STRESS</i>	<i>TEST COND</i>	<i>DIV</i>	<i>FUNCTION</i>	<i>DEVICE</i>	<i>EVAL #</i>	<i>DC</i>	<i>ASSY LOT</i>	<i>FAB</i>	<i>PKG</i>	<i>PKG</i>	<i># PINs</i>	<i>DURATION</i>	<i>SAMP</i>	<i>REJ</i>	<i>FAILURE MODE</i>
Wfr Process ID: SRAM/LOGIC-R42H															
T/C3	150C/-65C	MPD	SRAM	CY62256-SNC	MR001166	9949	619935207	MN	NSOIC	CSPI-R	28	300	45	0	
	150C/-65C	MPD	SRAM	CY62256-SNC	MR001217	0005	510000798	MN	NSOIC	INDNS-O	28	300	45	0	
	150C/-65C	MPD	SRAM	CY62256-SNI	MR94181	9942	519915797	MN	SOIC	INDNS-O	28	300	45	0	
	150C/-65C	MPD	SRAM	CY62256-ZC	MR001109	9952	619938545	MN	TSOP	CSPI-R	28	300	45	0	

Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
Wfr Process ID: SRAM/LOGIC-R42HD															
EFRA	150C/5.75	MPD	SRAM	CY7C199-VC	MR93075	9929	619920539	MN	SOJ	CSPI-R	28	48	150	0	
	150C/5.75V	MPD	SRAM	CY7C1049-VCB	99452	9946	619934257	MN	SOJ	CSPI-R	36	48	1099	0	
	150C/5.75V	MPD	SRAM	CY7C109-VC	99452	9947	519918323	MN	SOJ	INDNS-O	32	48	3073	0	
	150C/5.75V	MPD	SRAM	CY7C109-VC	99452	9947	519918324	MN	SOJ	INDNS-O	32	48	2945	1	1 Particle Defect
	150C/5.75V	MPD	SRAM	CY7C109-VC	99452	9947	519918326	MN	SOJ	INDNS-O	32	48	1952	2	2 Destroyed During Analysis
HAST	130C/5.5V	MPD	SRAM	CY7C1009-VC	MR001082	9951	619936395	MN	SOJ	CSPI-R	32	128	45	0	
	130C/5.5V	MPD	SRAM	CY7C1020-VC	MR94091	9933	619922192	MN	SOJ	TAIWN-G	44	128	41	0	
	130C/5.5V	MPD	SRAM	CY7C1020-ZSC	MR001155	0002	610000702	MN	TSOP II	CSPI-R	44	128	45	1	1 UNKNOWN
	130C/5.5V	MPD	SRAM	CY7C1049-VCB	99452	9946	619934257	MN	SOJ	CSPI-R	36	128	47	0	
	130C/5.5V	MPD	SRAM	CY7C109-VIB	99112	9932	519913378	MN	SOJ	INDNS-O	32	128	50	0	
	130C/5.5V	MPD	SRAM	CY7C109-ZC	99511	9952	619939442	MN	TSOP	TAIWN-T	32	128	50	0	
	130C/5.5V	MPD	SRAM	CY7C199-VC	000405	9949	619936486	MN	SOJ	CSPI-R	28	128	45	0	
	130C/5.5V	MPD	SRAM	CY7C199-VC	000405	9949	619936849	MN	SOJ	CSPI-R	28	128	46	0	
	130C/5.5V	MPD	SRAM	CY7C199-VC	000405	9949	619936855	MN	SOJ	CSPI-R	28	128	45	0	
	130C/5.5V	MPD	SRAM	CY7C199-VC	MR94189	9942	619929685	MN	TSOP	CSPI-R	28	128	41	0	2-EOS
	130C/5.5V	MPD	SRAM	CY7C199-VI	MR001255	0006	610004663	MN	SOJ	CSPI-R	28	128	45	0	
	140C/5.5V	MPD	SRAM	CY7C109-VC	99112	9915	619906538	MN	SOJ	INDNS-O	32	128	48	0	
HTS	150C/N/A	DCD	DPORT	CY7C09379V-AC	MR94029	9932	619921143	MN	TQFP	TAIWN-G	100	500	43	0	
	150C/N/A	MPD	SRAM	CY7C1009-VC	MR001083	9951	619936395	MN	SOJ	CSPI-R	32	500	45	0	
	150C/N/A	MPD	SRAM	CY7C1020-ZSC	MR001156	0002	610000702	MN	TSOP II	CSPI-R	44	500	45	0	
	150C/N/A	MPD	SRAM	CY7C109-VC	MR001105	9950	519919324	MN	SOJ	INDNS-O	32	500	45	0	
	150C/N/A	MPD	SRAM	CY7C109-VC	MR94176	9942	519916020	MN	SOJ	INDNS-O	32	500	45	0	

Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
Wfr Process ID: SRAM/LOGIC-R42HD															
HTS	150C/N/A	MPD	SRAM	CY7C109-ZC	99511		619939442	MN	TSOP	TAIWN-T	32	500	52	0	
	150C/N/A	MPD	SRAM	CY7C109-ZC	99511		619939442	MN	TSOP	TAIWN-T	32	1000	52	0	
	165C/N/A	MPD	SRAM	CY7C109-VC	99112	9915	619906538	MN	SOJ	INDNS-O	32	336	48	0	
	165C/N/A	MPD	SRAM	CY7C109-VIB	99112	9932	519913378	MN	SOJ	INDNS-O	32	336	50	0	
	165C/N/A	MPD	SRAM	CY7C109-VIB	99112	9932	519913378	MN	SOJ	INDNS-O	32	1000	50	0	
LFRA	150C/5.75	MPD	SRAM	CY7C199-VC	MR93075	9929	619920539	MN	SOJ	CSPI-R	28	500	150	1	1 Unknown Cause
PCT	121C/100%RH	MPD	SRAM	CY7C1009-VC	MR001080	9951	619936395	MN	SOJ	CSPI-R	32	168	45	0	
	121C/100%RH	MPD	SRAM	CY7C1020-ZSC	MR001153	0002	610000702	MN	TSOP II	CSPI-R	44	168	45	1	1 Unknown Cause
	121C/100%RH	MPD	SRAM	CY7C1049-VCB	99452	9946	619934257	MN	SOJ	CSPI-R	36	168	47	0	
	121C/100%RH	MPD	SRAM	CY7C109-VC	MR001102	9950	519919324	MN	SOJ	INDNS-O	32	168	45	0	
	121C/100%RH	MPD	SRAM	CY7C109-ZC	99511	0002	619939441	MN	TSOP	TAIWN-T	32	168	48	0	
	121C/100%RH	MPD	SRAM	CY7C109-ZC	99511	0002	619939442	MN	TSOP	TAIWN-T	32	168	50	0	
	121C/100%RH	MPD	SRAM	CY7C109-ZC	99511	0002	619939443	MN	TSOP	TAIWN-T	32	168	50	0	
	121C/100%RH	MPD	SRAM	CY7C199-VC	000405	9949	619936955	MN	SOJ	CSPI-R	28	168	50	0	
	121C/100%RH	MPD	SRAM	CY7C199-VC	000405	9949	619936957	MN	SOJ	CSPI-R	28	168	50	0	
	121C/100%RH	MPD	SRAM	CY7C199-VC	000405	9952	619939305	MN	SOJ	CSPI-R	28	168	50	0	
T/C3	150C/-65C	DCD	DPORT	CY7C09379V-AC	MR94028	9932	619921143	MN	TQFP	TAIWN-G	100	300	43	0	
	150C/-65C	MPD	SRAM	CY7C1009-VC	MR001081	9951	619936395	MN	SOJ	CSPI-R	32	300	45	0	
	150C/-65C	MPD	SRAM	CY7C1020-VC	MR94090	9933	619922192	MN	SOJ	TAIWN-G	44	300	45	0	
	150C/-65C	MPD	SRAM	CY7C1021-VI	MR93124	9930	619919776	MN	SOJ	CSPI-R	44	300	45	0	
	150C/-65C	MPD	SRAM	CY7C1041-VC	MR94146	9939	619927406	MN	SOJ	CSPI-R	44	300	47	0	
	150C/-65C	MPD	SRAM	CY7C1049-VCB	99452	9946	619934257	MN	SOJ	CSPI-R	36	300	48	0	

Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
Wfr Process ID: SRAM/LOGIC-R42HD															
T/C3	150C/-65C	MPD	SRAM	CY7C1049-VCB	99452	9946	619934257	MN	SOJ	CSPI-R	36	500	48	0	
	150C/-65C	MPD	SRAM	CY7C1049-VCB	99452	9946	619934257	MN	SOJ	CSPI-R	36	1000	47	0	
	150C/-65C	MPD	SRAM	CY7C109-VC	99112	9915	619906538	MN	SOJ	INDNS-O	32	300	46	0	
	150C/-65C	MPD	SRAM	CY7C109-VC	99112	9915	619906538	MN	SOJ	INDNS-O	32	1000	46	0	
	150C/-65C	MPD	SRAM	CY7C109-VC	MR001103	9950	519919324	MN	SOJ	INDNS-O	32	300	45	0	
	150C/-65C	MPD	SRAM	CY7C109-VC	MR94174	9942	519916020	MN	SOJ	INDNS-O	32	300	45	0	
	150C/-65C	MPD	SRAM	CY7C109-VIB	99112	9916	619906498	MN	SOJ	INDNS-O	32	300	46	0	
	150C/-65C	MPD	SRAM	CY7C109-VIB	99112	9932	519913378	MN	SOJ	INDNS-O	32	300	50	0	
	150C/-65C	MPD	SRAM	CY7C109-VIB	99112	9932	519913378	MN	SOJ	INDNS-O	32	500	50	0	
	150C/-65C	MPD	SRAM	CY7C109-VIB	99112	9932	519913378	MN	SOJ	INDNS-O	32	1000	50	0	
	150C/-65C	MPD	SRAM	CY7C109-ZC	99511	0002	619939441	MN	TSOP	TAIWN-T	32	300	48	0	
	150C/-65C	MPD	SRAM	CY7C109-ZC	99511	0002	619939442	MN	TSOP	TAIWN-T	32	300	50	0	
	150C/-65C	MPD	SRAM	CY7C109-ZC	99511	0002	619939443	MN	TSOP	TAIWN-T	32	300	50	0	
	150C/-65C	MPD	SRAM	CY7C1351-AC	MR94131	9932	619919041	MN	TQFP	CSPI-R	100	300	47	2	2 Open- Heel or Neck Break
	150C/-65C	MPD	SRAM	CY7C199-VC	000405	9949	619936486	MN	SOJ	CSPI-R	28	300	48	0	
	150C/-65C	MPD	SRAM	CY7C199-VC	000405	9949	619936849	MN	SOJ	CSPI-R	28	300	50	0	
	150C/-65C	MPD	SRAM	CY7C199-VC	000405	9949	619936855	MN	SOJ	CSPI-R	28	300	50	0	
	150C/-65C	MPD	SRAM	CY7C199-VC	000405	9949	619936859	MN	SOJ	CSPI-R	28	300	50	0	
	150C/-65C	MPD	SRAM	CY7C199-VC	000405	9949	619936895	MN	SOJ	CSPI-R	28	300	50	0	
	150C/-65C	MPD	SRAM	CY7C199-VC	000405	9949	619936955	MN	SOJ	CSPI-R	28	300	47	0	
	150C/-65C	MPD	SRAM	CY7C199-VC	000405	9949	619936956	MN	SOJ	CSPI-R	28	300	50	0	
	150C/-65C	MPD	SRAM	CY7C199-VC	000405	9949	619936957	MN	SOJ	CSPI-R	28	300	50	0	

Quarterly Reliability Monitor Data - 00Q1

<i>STRESS</i>	<i>TEST COND</i>	<i>DIV</i>	<i>FUNCTION</i>	<i>DEVICE</i>	<i>EVAL #</i>	<i>DC</i>	<i>ASSY LOT</i>	<i>FAB</i>	<i>PKG</i>	<i>PKG</i>	<i># PINS</i>	<i>DURATION</i>	<i>SAMP</i>	<i>REJ</i>	<i>FAILURE MODE</i>
Wfr Process ID: SRAM/LOGIC-R42HD															
T/C3	150C/-65C	MPD	SRAM	CY7C199-VC	000405	9949	619936966	MN	SOJ	CSPI-R	28	300	50	0	
	150C/-65C	MPD	SRAM	CY7C199-VC	000405	9949	619937048	MN	SOJ	CSPI-R	28	300	49	0	

Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
Wfr Process ID: SRAM/LOGIC-R52D-3															
EFRA	150C/3.8V	DCD	DPORT	CY7C056V-ACB	99491	9946	619932870	MN	TQFP	TAIWN-G	100	48	80	0	
	150C/3.8V	MPD	SRAM	CY7C1325B-ACB	99503		619927801	MN	TQFP	CSPI-R	100	48	1799	0	
	150C/3.8V	MPD	SRAM	CY7C1338B-AC	99503	9946	619934137	MN	TQFP	CSPI-R	100	48	1500	0	
HAST	130C/3.63V	MPD	SRAM	CY7C1049BV33-VC	000305	9936	619925327	MN	SOJ	CSPI-R	36	128	50	0	
	130C/3.63V	MPD	SRAM	CY7C1325B-ACB	99503	9918	619910139	MN	TQFP	CSPI-R	100	128	47	0	
LFRA	150C/3.8V	MPD	SRAM	CY7C1049BV33-VC	000305	9949	619937741	MN	SOJ	CSPI-R	36	80	530	0	
	150C/3.8V	MPD	SRAM	CY7C1049BV33-VC	000305	9949	619937741	MN	SOJ	CSPI-R	36	500	530	0	
	150C/3.8V	MPD	SRAM	CY7C1325B-ACB	99503		619927801	MN	TQFP	CSPI-R	100	80	400	0	
	150C/3.8V	MPD	SRAM	CY7C1325B-ACB	99503		619927801	MN	TQFP	CSPI-R	100	500	400	2	2 Lost Device
	150C/3.8V	MPD	SRAM	CY7C1338B-AC	99503	9946	619934137	MN	TQFP	CSPI-R	100	80	400	0	
	150C/3.8V	MPD	SRAM	CY7C1338B-AC	99503	9946	619934137	MN	TQFP	CSPI-R	100	500	400	0	
PCT	121C/100%RH	MPD	SRAM	CY7C1049BV33-VC	000305	9936	619925327	MN	SOJ	CSPI-R	36	168	48	0	
	121C/100%RH	MPD	SRAM	CY7C1325B-ACB	99503	9914	619907775	MN	TQFP	CSPI-R	100	168	47	0	
	121C/100%RH	MPD	SRAM	CY7C1329-AC	MR001222	0004	610000079	MN	TQFP	TAIWN-G	100	168	45	0	
T/C3	150C/-65C	MPD	SRAM	CY7C1049BV33-VC	000305	9936	619925327	MN	SOJ	CSPI-R	36	300	48	0	
	150C/-65C	MPD	SRAM	CY7C1049BV33-VC	000305	9936	619925327	MN	SOJ	CSPI-R	36	500	48	0	
	150C/-65C	MPD	SRAM	CY7C1049BV33-VC	000305	9936	619925327	MN	SOJ	CSPI-R	36	1000	48	0	
	150C/-65C	MPD	SRAM	CY7C1325B-ACB	99503	9914	619907775	MN	TQFP	CSPI-R	100	300	40	0	7 EOS
	150C/-65C	MPD	SRAM	CY7C1325B-ACB	99503	9918	619910139	MN	TQFP	CSPI-R	100	300	47	0	
	150C/-65C	MPD	SRAM	CY7C1325B-ACB	99503	9918	619910139	MN	TQFP	CSPI-R	100	500	47	0	
	150C/-65C	MPD	SRAM	CY7C1325B-ACB	99503	9918	619910139	MN	TQFP	CSPI-R	100	1000	47	0	

Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
Wfr Process ID: SRAM/LOGIC-R52H															
EFRA	150C/3.8V	MPD	SRAM	CY62128B-SC	001102	0009	610006394	MN	SOIC	TAIWN-G	32	48	1090	0	1 Good Device
	150C/3.8V	MPD	SRAM	CY62128B-SC	001102	0009	610006395	MN	SOIC	TAIWN-G	32	48	1074	0	
	150C/3.8V	MPD	SRAM	CY62128B-SC	001102	0009	610007711	MN	SOIC	TAIWN-G	32	48	1088	0	
	150C/3.8V	MPD	SRAM	CY62128B-SC	001102	9947	619933589	MN	SOIC	TAIWN-G	32	48	1098	0	
	150C/3.8V	MPD	SRAM	CY62128B-SC	001102	9947	619933593	MN	SOIC	TAIWN-G	32	48	2186	2	2 Poly Defect
	150C/3.8V	MPD	SRAM	CY62128B-SC	001102	9947	619933598	MN	SOIC	TAIWN-G	32	48	1097	0	

Quarterly Reliability Monitor Data - 00Q1

STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINs	DURATION	SAMP	REJ	FAILURE MODE
Wfr Process ID: SRAM/LOGIC-R52LD-3															
EFRA	150C/3.8V	MPD	SRAM	CY62137VL-BAI	000204		610002413	MN	FPBGA	CSPI-R	48	48	544	0	
	150C/3.8V	MPD	SRAM	CY62137VL-BAI	000204		619938755	MN	FPBGA	CSPI-R	48	48	339	1	1 Particle Defect
	150C/3.8V	MPD	SRAM	CY62137VL-BAI	000204		619938874	MN	FPBGA	CSPI-R	48	48	402	0	
	150C/3.8V	MPD	SRAM	CY62137VL-BAI	000204		619938875	MN	FPBGA	CSPI-R	48	48	281	0	
	150C/3.8V	MPD	SRAM	CY62137VL-ZSIB	99357	9949	619935917	MN	TSOP II	CSPI-R	44	48	3176	0	
	150C/3.8V	MPD	SRAM	CY62137VL-ZSIB	99357	9949	619935918	MN	TSOP II	CSPI-R	44	48	3313	0	
HAST	130C/3.63V	MPD	SRAM	CY62137VL-BAI	000204	0001	619938755	MN	FPBGA	CSPI-R	48	128	50	0	
	130C/3.63V	MPD	SRAM	CY62137VL-BAI	000204	0001	619938755	MN	FPBGA	CSPI-R	48	128	48	0	
	130C/3.63V	MPD	SRAM	CY62137VL-BAI	000204	0001	619938875	MN	FPBGA	CSPI-R	48	128	47	0	
	130C/3.63V	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925644	MN	FPBGA	TAIWN-G	48	128	54	0	
HTS	150C/N/A	MPD	SRAM	CY62137VL-BAI	000204		619938755	MN	FPBGA	CSPI-R	48	500	50	0	
	150C/N/A	MPD	SRAM	CY62137VL-BAI	000204		619938755	MN	FPBGA	CSPI-R	48	1000	50	0	
	150C/N/A	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925644	MN	FPBGA	TAIWN-G	48	336	48	0	
	150C/N/A	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925644	MN	FPBGA	TAIWN-G	48	500	48	0	
	150C/N/A	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925644	MN	FPBGA	TAIWN-G	48	1000	48	0	
LFRA	150C/3.8V	MPD	SRAM	CY62137VL-BAI	000204		619938755	MN	FPBGA	CSPI-R	48	80	120	0	
	150C/3.8V	MPD	SRAM	CY62137VL-BAI	000204		619938755	MN	FPBGA	CSPI-R	48	500	120	0	
	150C/3.8V	MPD	SRAM	CY62137VL-BAI	000204		619938874	MN	FPBGA	CSPI-R	48	80	120	0	
	150C/3.8V	MPD	SRAM	CY62137VL-BAI	000204		619938874	MN	FPBGA	CSPI-R	48	500	118	0	
	150C/3.8V	MPD	SRAM	CY62137VL-BAI	000204		619938875	MN	FPBGA	CSPI-R	48	80	120	0	
	150C/3.8V	MPD	SRAM	CY62137VL-BAI	000204		619938875	MN	FPBGA	CSPI-R	48	500	120	0	

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STRESS	TEST COND	DIV	FUNCTION	DEVICE	EVAL #	DC	ASSY LOT	FAB	PKG	PKG	# PINS	DURATION	SAMP	REJ	FAILURE MODE
Wfr Process ID: SRAM/LOGIC-R52LD-3															
PCT	121C/100%RH	MPD	SRAM	CY62137VL-BAI	000204		619938755	MN	FPBGA	CSPI-R	48	168	50	0	
	121C/100%RH	MPD	SRAM	CY62137VL-BAI	000204		619938875	MN	FPBGA	CSPI-R	48	168	50	0	
	121C/100%RH	MPD	SRAM	CY62137VL-BAI	MR001087	9949	619937534	MN	FPBGA	TAIWN-G	48	168	45	0	
	121C/100%RH	MPD	SRAM	CY62137VL-BAI	MR001091	9949	619937436	MN	FPBGA	TAIWN-T	48	168	45	0	
	121C/100%RH	MPD	SRAM	CY62137VL-BAI	MR94267	9941	619929591	MN	FPBGA	TAIWN-T	48	168	45	0	
	121C/100%RH	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925642	MN	FPBGA	TAIWN-G	48	168	50	0	
T/C2	125C/-55C	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925642	MN	FPBGA	TAIWN-G	48	500	48	0	
	125C/-55C	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925642	MN	FPBGA	TAIWN-G	48	1000	47	0	
	125C/-55C	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925642	MN	FPBGA	TAIWN-G	48	1500	47	0	
	125C/-55C	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925643	MN	FPBGA	TAIWN-G	48	500	47	0	
	125C/-55C	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925643	MN	FPBGA	TAIWN-G	48	1000	47	0	
	125C/-55C	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925643	MN	FPBGA	TAIWN-G	48	1500	47	0	
	125C/-55C	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925644	MN	FPBGA	TAIWN-G	48	500	48	1	1 Destroyed During Analysis
	125C/-55C	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925644	MN	FPBGA	TAIWN-G	48	1000	48	0	
	125C/-55C	MPD	SRAM	CY62146VLL-BAIB	99331	9938	619925644	MN	FPBGA	TAIWN-G	48	1500	47	0	
T/C3	150C/-65C	MPD	SRAM	CY62137VL-BAI	000204		619938755	MN	FPBGA	CSPI-R	48	300	47	0	
	150C/-65C	MPD	SRAM	CY62137VL-BAI	000204		619938874	MN	FPBGA	CSPI-R	48	300	50	0	
	150C/-65C	MPD	SRAM	CY62137VL-BAI	000204		619938875	MN	FPBGA	CSPI-R	48	300	47	0	